

<b>Notice of References Cited</b>	Application/Control No. 10/776,170	Applicant(s)/Patent Under Reexamination HAKKINEN ET AL.	
	Examiner Edan Orgad	Art Unit 2684	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2005/0213575	09-2005	Shin et al.	370/389
	B	US-2005/0180384	08-2005	Jeong et al.	370/350
	C	US-2004/0240400	12-2004	Khan, Farooq Ullah	370/280
	D	US-2004/0202147	10-2004	Hakkinen et al.	370/351
	E	US-2004/0116143	06-2004	Love et al.	455/522
	F	US-2002/0046379	04-2002	Miki et al.	714/749
	G	US-2002/0172217	11-2002	Kadaba et al.	370/443
	H	US-2003/0045288	03-2003	Luschi et al.	455/434
	I	US-2003/0189918	10-2003	Das et al.	370/349
	J	US-2003/0228876	12-2003	Hwang, Woonhee	455/522
	K	US-2004/0009767	01-2004	Lee et al.	455/422.1
	L	US-2004/0203980	10-2004	Das et al.	455/522
	M	US-2004/0223507	11-2004	Kuchibhotla et al.	370/428

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.